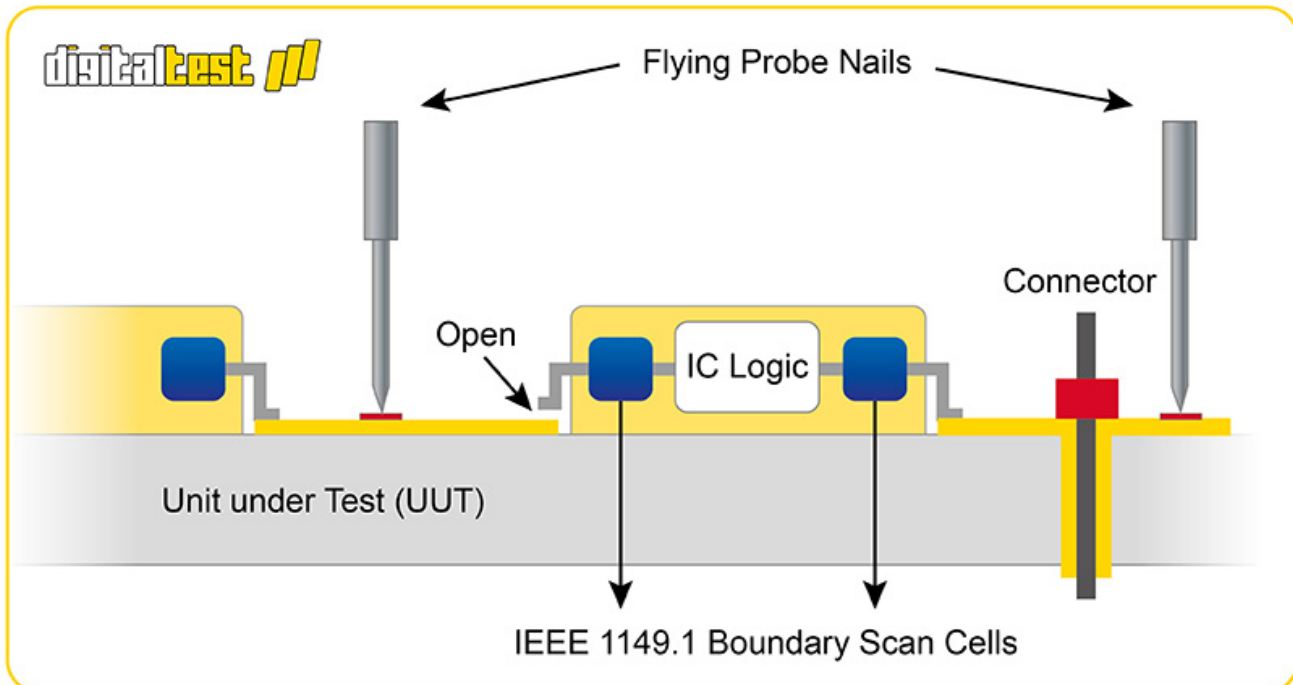


## Boundary Scan for Flying Probe tests



With the boundary scan upgrade to our Flying Probe the needles can act as virtual JTAG/Boundary Scan cells. This increases fault coverage, since now the conductor paths that otherwise could not be reached can also be tested

- > Shortens test times as well as time-to-market
- > Enables very high fault coverage even for highly compact flat modules
- > Incorporates all functions in CITE – production remains in the familiar user interface
- > Simple data export with C-LINK for boundary scan software
- > Fast system diagnostics for error conditions
- > All JTAG/Boundary Scan test and programming procedures can be reused

Our main partners in matters of JTAG/Boundary Scan integration are the respected [GÖPEL electronic](#) and [JTAG Technologies](#).